General Description

The 830211 is a 1-to-1 Differential-to-LVCMOS/ LVTTL Translator and a member of the family of High Performance Clock Solutions from IDT. The differential input is highly flexible and can accept the following input types: LVPECL, LVDS, LVHSTL, SSTL, and HCSL. The small 8-lead SOIC footprint makes this device ideal for use in applications with limited board space.

Features

- One LVCMOS/LVTTL output
- Differential CLK/nCLK input pair
- CLK/nCLK pair can accept the following differential input levels: LVPECL, LVDS, LVHSTL, SSTL, HCSL
- Output frequency: 350MHz (typical)
- Part-to-part skew: 500ps (maximum)
- Additive phase jitter, RMS: 0.21ps (typical), 3.3V output
- Full 3.3V and 2.5V operating supply
- -40°C to 85°C ambient operating temperature

Block Diagram

CLK Pulldown nCLK Pullup Q0

Pin Assignment



830211

8-Lead SOIC, 150Mil 3.9mm x 4.9mm x 1.375mm package body M Package Top View

Table 1. Pin Descriptions

Number	Name	Туре		Description
1, 4, 6	nc	Unused		No connect.
2	CLK	Input	Pulldown	Non-inverting differential clock input.
3	nCLK	Input	Pullup	Inverting differential clock input.
5	GND	Power		Power supply ground.
7	Q0	Output		Single-ended clock output. LVCMOS/LVTTL interface levels.
8	V _{DD}	Power		Positive supply pin.

NOTE: Pullup and Pulldown refer to internal input resistors. See Table 2, Pin Characteristics, for typical values.

Table 2. Pin Characteristics

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C _{IN}	Input Capacitance			4		pF
R _{PULLUP}	Input Pullup Resistor			51		kΩ
R _{PULLDOWN}	Input Pulldown Resistor			51		kΩ
C _{PD}	Power Dissipation Capacitance	V _{DD} = 3.6V		23		pF
R _{OUT}	Output Impedance		5	7	12	Ω

Absolute Maximum Ratings

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics or AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, V _{DD}	4.6V
Inputs, V _I	-0.5V to V _{DD} + 0.5V
Outputs, V _O	-0.5V to V _{DD} + 0.5V
Package Thermal Impedance, θ_{JA}	103°C/W (0 lfpm)
Storage Temperature, T _{STG}	-65°C to 150°C

DC Electrical Characteristics

Table 3A. Power Supply DC Characteristics, V_{DD} = $3.3V \pm 0.3V$ or $2.5V \pm 5\%$, T_A = -40°C to $85^{\circ}C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V Desitive Supply Velter	Positive Supply Voltage		3.0	3.3	3.6	V
V _{DD}	Positive Supply Voltage		2.375	2.5	2.625	V
I _{DD}	Power Supply Current				20	mA

Table 3B. LVCMOS/LVTTL DC Characteristics, V_{DD} = $3.3V \pm 0.3V$ or $2.5V \pm 5\%$, T_A = -40°C to 85° C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V	Output High Voltage; NOTE 1	V _{DD} = 3.6V	2.6			V
V _{OH}		V _{DD} = 2.625V	1.8			V
V _{OL}	Output Low Voltage; NOTE 1	V _{DD} = 3.6V or 2.625V			0.5	V

NOTE 1: Outputs terminated with 50Ω to V_{DD}/2. See Parameter Measurement Information, Output Load Test Circuit Diagrams.

Table 3C. Differential DC Characteristics, V_{DD} = $3.3V \pm 0.3V$ or $2.5V \pm 5\%$, T_A = -40°C to $85^{\circ}C$

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
	Input High Current	nCLK	$V_{IN} = V_{DD} = 3.6V \text{ or } 2.625V$			5	μA
ΊΗ	Input High Current	CLK	$V_{IN} = V_{DD} = 3.6V \text{ or } 2.625V$			150	μA
	Input Low Cureent	nCLK	$V_{IN} = 0V, V_{DD} = 3.6V \text{ or } 2.625V$	-150			μA
ΊL		CLK	$V_{IN} = 0V, V_{DD} = 3.6V \text{ or } 2.625V$	-5			μA
V _{PP}	Peak-to-Peak Input V	oltage		0.15		1.3	V
V _{CMR}	Common Mode Input Voltage; NOTE 1, 2			GND + 0.5		V _{DD} – 0.85	V

NOTE 1: For single ended applications, the maximum input voltage for CLK, nCLK is V_{DD} + 0.3V.

NOTE 2: Common mode voltage is defined as $\ensuremath{\mathsf{V}_{\mathsf{IH}}}$.

AC Electrical Characteristics

Table 4A. AC Characteristics, $V_{DD} = 3.3V \pm 0.3V$, $T_A = -40^{\circ}C$ to $85^{\circ}C$

Parameter	Symbol	Test Conditions	Minimum	Typical	Maximum	Units
f _{MAX}	Output Frequency			350		MHz
t _{PD}	Propagation Delay, NOTE 1	$f \leq 350 MHz$	1.7	2.0	2.3	ns
<i>t</i> sk(pp)	Part-to-Part Skew; NOTE 2, 3				500	ps
<i>t</i> jit	Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter Section	100MHz, Integration Range (637kHz – 10MHz)		0.21		ps
t _R / t _F	Output Rise/Fall Time	0.8V to 2V	100	250	400	ps
odc	Output Duty Ovela	$f \le 166 MHz$	45	50	55	%
	Output Duty Cycle	166MHz < <i>f</i> ≤ 350MHz	40	50	60	%

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

All parameters measured at f_{MAX} unless noted otherwise.

NOTE 1: Measured from the differential input crossing point to the output at $V_{DD}/2$.

NOTE 2: Defined as skew between outputs on different devices operating at the same supply voltage and with equal load conditions. Using the same type of inputs on each device, the outputs are measured at $V_{DD}/2$.

NOTE 3: This parameter is defined in accordance with JEDEC Standard 65.

Table 4B. AC Characteristics, V_{DD} = 2.5V ± 5%, T_A = -40°C to 85°C

Parameter	Symbol	Test Conditions	Minimum	Typical	Maximum	Units
f _{MAX}	Output Frequency			350		MHz
t _{PD}	Propagation Delay, NOTE 1	$f \le 350 \text{MHz}$	1.9	2.2	2.5	ns
<i>t</i> sk(pp)	Part-to-Part Skew; NOTE 2, 3				500	ps
<i>t</i> jit	Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter Section	100MHz, Integration Range (637kHz – 10MHz)		0.21		ps
t _R / t _F	Output Rise/Fall Time	20% to 80%	250		550	ps
odc	Output Duty Ovela	$f \le 250 \text{MHz}$	45	50	55	%
odc	Output Duty Cycle	250MHz < <i>f</i> ≤ 350MHz	40	50	60	%

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

All parameters measured at f_{MAX} unless noted otherwise.

NOTE 1: Measured from the differential input crossing point to the output at $V_{DD}/2$.

NOTE 2: Defined as skew between outputs on different devices operating at the same supply voltage and with equal load conditions. Using the same type of inputs on each device, the outputs are measured at $V_{DD}/2$.

NOTE 3: This parameter is defined in accordance with JEDEC Standard 65.

Additive Phase Jitter

The spectral purity in a band at a specific offset from the fundamental compared to the power of the fundamental is called the *dBc Phase Noise*. This value is normally expressed using a Phase noise plot and is most often the specified plot in many applications. Phase noise is defined as the ratio of the noise power present in a 1Hz band at a specified offset from the fundamental frequency to the power value of the fundamental. This ratio is expressed in decibels (dBm) or a ratio of the power in the 1Hz band

to the power in the fundamental. When the required offset is specified, the phase noise is called a *dBc* value, which simply means dBm at a specified offset from the fundamental. By investigating jitter in the frequency domain, we get a better understanding of its effects on the desired application over the entire time record of the signal. It is mathematically possible to calculate an expected bit error rate given a phase noise plot.



As with most timing specifications, phase noise measurements has issues relating to the limitations of the equipment. Often the noise floor of the equipment is higher than the noise floor of the

device. This is illustrated above. The device meets the noise floor of what is shown, but can actually be lower. The phase noise is dependent on the input source and measurement equipment.

Parameter Measurement Information



3.3V Core/3.3V LVCMOS Output Load AC Test Circuit



Differential Input Level



3.3V Output Rise/Fall Time



2.5V Core/2.5V LVCMOS Output Load AC Test Circuit



Part-to-Part Skew



2.5V Output Rise/Fall Time

Parameter Measurement Information, continued





Propagation Delay

Output Duty Cycle/Pulse Width/Period

Application Information

Wiring the Differential Input to Accept Single Ended Levels

Figure 1 shows how the differential input can be wired to accept single ended levels. The reference voltage V_REF = $V_{DD}/2$ is generated by the bias resistors R1, R2 and C1. This bias circuit should be located as close as possible to the input pin. The ratio of R1 and R2 might need to be adjusted to position the V_REF in the center of the input voltage swing. For example, if the input clock swing is only 2.5V and V_{DD} = 3.3V, V_REF should be 1.25V and R2/R1 = 0.609.



Figure 1. Single-Ended Signal Driving Differential Input

Differential Clock Input Interface

The CLK /nCLK accepts LVDS, LVPECL, LVHSTL, SSTL, HCSL and other differential signals. Both signals must meet the V_{PP} and V_{CMR} input requirements. *Figures 2A to 2F* show interface examples for the HiPerClockS CLK/nCLK input driven by the most common driver types. The input interfaces suggested here are examples only. Please consult with the vendor of the driver



Figure 2A. HiPerClockS CLK/nCLK Input Driven by an IDT Open Emitter HiPerClockS LVHSTL Driver



Figure 2C. HiPerClockS CLK/nCLK Input Driven by a 3.3V LVPECL Driver



Figure 2E. HiPerClockS CLK/nCLK Input Driven by a 3.3V HCSL Driver

component to confirm the driver termination requirements. For example, in Figure 2A, the input termination applies for IDT HiPerClockS open emitter LVHSTL drivers. If you are using an LVHSTL driver from another vendor, use their termination recommendation.



Figure 2B. HiPerClockS CLK/nCLK Input Driven by a 3.3V LVPECL Driver



Figure 2D. HiPerClockS CLK/nCLK Input Driven by a 3.3V LVDS Driver



Figure 2F. HiPerClockS CLK/nCLK Input Driven by a 2.5V SSTL Driver

Reliability Information

Table 5. θ_{JA} vs. Air Flow Table for an 8 Lead SOIC

	θ_{JA} by Velocity		
Linear Feet per Minute	0	200	500
Single-Layer PCB, JEDEC Standard Test Boards	123°C/W	110°C/W	99°C/W
Multi-Layer PCB, JEDEC Standard Test Boards	103°C/W	94°C/W	89°C/W

Transistor Count

The transistor count for 830211 is: 416 Pin-to-pin compatible with the MC100EPT21

Package Outline and Package Dimensions

Package Outline - M Suffix for 8 Lead SOIC





Table 6. Package Dimensions

All Dimensions in Millimeters						
Symbol	Symbol Minimum Maximum					
Ν		8				
Α	1.35	1.75				
A1	0.10	0.25				
В	0.33 0.51					
С	0.19	0.25				
D	4.80	5.00				
E	3.80	4.00				
e	1.27	Basic				
Н	5.80	6.20				
h	0.25	0.50				
L	0.40	1.27				
α	0°	8°				

Reference Document: JEDEC Publication 95, MS-012

Ordering Information

Table 7. Ordering Information

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
83021AMILF	83021AIL	"Lead-Free" 8 Lead SOIC	Tube	-40°C to 85°C
83021AMILFT	83021AIL	"Lead-Free" 8 Lead SOIC	Tape & Reel	-40°C to 85°C

Revision History Sheet

Rev	Table	Page	Description of Change	Date
В	T2 T3B T3C T3D T4B	2 3 3 4 5 6 7	Pin Characteristics table - added 2.5V C _{PD} . Added 2.5V Power Supply table. LVCMOS table - added 2.5V V _{OH} . Differential table - added 2.5V. Added 2.5V AC Characteristics table. Added 2.5V Output Load AC Test Circuit Diagram, and 2.5V Output Rise/Fall Time Diagrams. Updated Figure 1. Added Differential Clock Input Interface section.	6/3/04
В	T4A	2 4	Pin Characteristics Table - changed C _{IN} 4pF max. to 4pF typical. 3.3V AC Characteristics Table - changed odc Test Conditions.	6/30/04
В	T7	1 10	Features Section - added Lead-Free bullet. Ordering Information Table - Added Lead-Free part number.	3/21/05
С	T4A, T4B T7	1 4 5 11	Features Section - added Additive Phase Jitter bullet. AC Characteristics Tables - added Additive Phase Jitter row. Added Additive Phase Jitter Plot. Added Lead-Free Note.	12/12/05
С		1 8 9	Pin Assignment - corrected package body measurements. Updated <i>Differential Clock Input Interface.</i> Updated <i>Reliability Information.</i> Updated datasheet format.	6/18/08
С	T4A, T4B	1 4	Corrected typo in Header from 1-to-2 to 1-to-1 AC Tables - added Temperature NOTE.	10/31/08
D	T7	10	Remove leaded orderable parts from Ordering Information table	11/14/12
D		1	Features section - removed leaded part note. Description - removed chip	4/23/14
D	Τ7	1 10	Removed HiPerClockS from General Description. Ordering Information - removed 2500 from Tape and Reel. Updated Datasheet header and footer.	12/14/15



Corporate Headquarters 6024 Silver Creek Valley Road San Jose, CA 95138 USA www.IDT.com

Sales

1-800-345-7015 or 408-284-8200 Fax: 408-284-2775 www.IDT.com/go/sales

Tech Support www.idt.com/go/support

DISCLAIMER Integrated Device Technology, Inc. (IDT) reserves the right to modify the products and/or specifications described herein at any time, without notice, at IDT's sole discretion. Performance specifications and operating parameters of the described products are determined in an independent state and are not guaranteed to perform the same way when installed in customer products. The information contained herein is provided without representation or warranty of any kind, whether express or implied, including, but not limited to, the suitability of IDT's products for any particular purpose, an implied warranty of merchantability, or non-infringement of the intellectual property rights of others. This document is presented only as a guide and does not convey any license under intellectual property rights of IDT or any third parties.

IDT's products are not intended for use in applications involving extreme environmental conditions or in life support systems or similar devices where the failure or malfunction of an IDT product can be reasonably expected to significantly affect the health or safety of users. Anyone using an IDT product in such a manner does so at their own risk, absent an express, written agreement by IDT.

Integrated Device Technology, IDT and the IDT logo are trademarks or registered trademarks of IDT and its subsidiaries in the United States and other countries. Other trademarks used herein are the property of IDT or their respective third party owners.

For datasheet type definitions and a glossary of common terms, visit www.idt.com/go/glossary.

Copyright ©2015 Integrated Device Technology, Inc. All rights reserved.



Мы молодая и активно развивающаяся компания в области поставок электронных компонентов. Мы поставляем электронные компоненты отечественного и импортного производства напрямую от производителей и с крупнейших складов мира.

Благодаря сотрудничеству с мировыми поставщиками мы осуществляем комплексные и плановые поставки широчайшего спектра электронных компонентов.

Собственная эффективная логистика и склад в обеспечивает надежную поставку продукции в точно указанные сроки по всей России.

Мы осуществляем техническую поддержку нашим клиентам и предпродажную проверку качества продукции. На все поставляемые продукты мы предоставляем гарантию.

Осуществляем поставки продукции под контролем ВП МО РФ на предприятия военно-промышленного комплекса России, а также работаем в рамках 275 ФЗ с открытием отдельных счетов в уполномоченном банке. Система менеджмента качества компании соответствует требованиям ГОСТ ISO 9001.

Минимальные сроки поставки, гибкие цены, неограниченный ассортимент и индивидуальный подход к клиентам являются основой для выстраивания долгосрочного и эффективного сотрудничества с предприятиями радиоэлектронной промышленности, предприятиями ВПК и научноисследовательскими институтами России.

С нами вы становитесь еще успешнее!

Наши контакты:

Телефон: +7 812 627 14 35

Электронная почта: sales@st-electron.ru

Адрес: 198099, Санкт-Петербург, Промышленная ул, дом № 19, литера Н, помещение 100-Н Офис 331